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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ion Serial No. 09/332,271 ig Date June 11, 1999 Examiner Ron E. Pompev Title: Methods for Forming Wordlines, Transistor Gates, and Conductive Interconnects. and Wordline, Transistor Gate, and Conductive Interconnect Structures

References -- See Attached Form PTO-1449

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

attached form PTO-1449 is submitted in compliance 37 CFR §1.56. No admission is made regarding whether any of the submitted references is prior art. Copies of the references are attached.

Respectfully Submitted:

Dated:__/2-/3-02

D. Brent Kenady Reg. No. 40,045

UNITED STATES PATENT AND TRADEMARK OFFICE

Application Derial No. 09/332,271 Filing Date June 11, 1999 Assignee Micron Technology, Inc. Examiner Ron E. Pompey Title: Methods for Forming Wordlines, Transistor Gates, and Conductive Interconnects,

and Wordline, Transistor Gate, and Conductive Interconnect Structures

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

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Respectfully Submitted:

Dated: 5-6-02

D. Brent Kenady Reg. No. 40,045



UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No
Filing Date June 11, 1999
Inventor
Assignee Micron Technology, Inc.
Group Art Unit
Examiner Ron E. Pompey
Attorney's Docket No Mi22-532
Title: Methods for Forming Wordlines, Transistor Gates, and Conductive Interconnects,
and Wordline, Transistor Gate, and Conductive Interconnect Structures

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether any of the submitted references is prior art. Copies of the references are attached.

Respectfully Submitted:

Dated: 3-13-02

D. Brent Kenady Reg. No. 40,045

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE Application Serial No. 09/322,271 Filing Date June 11, 1999 Inventor Klaus Florian Schuegraf et al. Assignee Micron Technology, Inc. Group Art Unit 2812 Examiner Ron E. Pompey Attorney's Docket No. MI22-532 Title: Methods for Forming Wordlines, Transistor Gates, and Conductive Interconnects, and Wordline, Transistor Gate, and Conductive Interconnect Structures

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether any of the submitted references is prior art. Copies of the references are attached.

Respectfully Submitted:

Dated: 2-7-02

D. Brent Kenady Reg. No. 40,045

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1	Inventor: Klass Florian Schuegraf et al.
2	Title: Methods For Forming Wordlines, Transistor Gates, And Conductive
3	Interconnects, And Wordline, Transistor Gate, and Conductive
4	Interconnect Structures
5	Assignee: Micron Technology, Inc.
6	
7	INFORMATION DISCLOSURE STATEMENT
8	The Examiner's attention is directed to the references listed on the attached
9	Form PTO-1449 and copies of which are attached.
10	Citation of these references are respectfully requested.
11	
12	Respectfully submitted,
13	(1/1/9a (); 12c
14	Date: Now Attorney: David G. Latwesen, Ph.D.
15	Reg. No. 38,533
16	
17	Date: Inventor: Klaus Florian Schuegraf
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Date: 5 24 99

Inventor:

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OF ART CITED BY APPLICANT
(Use several sees if necessary) MI22-532 Form PTO-1449 U.S. DEPARTMENT OF COMMERCE SERIAL NO. PATENT AND TRADEMARK OFFICE Unknown APPLICANT Klaus Florian Schuegraf et al. FILING DATE GROUP Filed herewith Unknown U.S. PATENT DOCUMENTS *Examiner Document Date Name Class Subclass Filing Date Initial Number If Appropriate 5,425,392 06/95 Thakur et al. ABAC AD ΑE ΑF AGAH ΑI AJ ΑK FOREIGN PATENT DOCUMENTS Document Country Class Subclass Translation Number No ΑL OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AK Taishi Kubota et al.; "The Effect of the Floating Gate/Tunnel SiO, Interface on FLASH Memory Data Retention Reliability"; 1994; 2 pages AL Shoue Jen Wang et al.: "Effects of Poly Depletion on the Estimate of Thin Dielectric Lifetime"; IEEE Electron Device Letters, Vol. 12, No. 11, November 1991; pp. 617-619 AM Klaus F. Schuegraf et al.; "Impact of Polysilicon Depletion in Thin Oxide MOS Technology", 1993; pp. 86-88 H E. H. Snow et al.; "Polarization Phenomena and Other Properties of Phosphosilicate Glass Films on Silicon"; Journal of the Electrochemical ANSociety, March 1966; pp. 263-269 П **EXAMINER** DATE CONSIDERED *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance aits and conformance with MPEP 609. Include copy of this form with next communication to applicant. 2800